Welcome to Galaxy Examinator reports

Date: Wed Oct 16 16:40:27 2024
Product :
LotID :

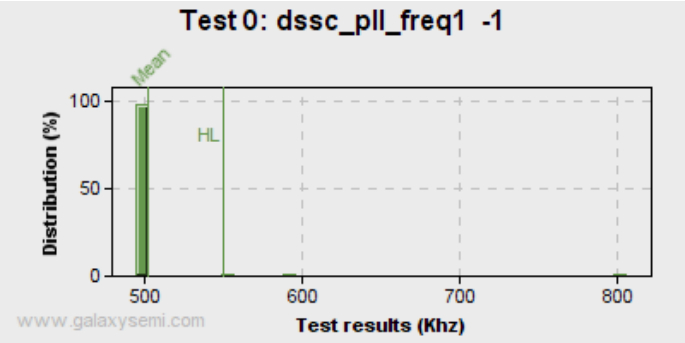
Table of contents

Tests Statistics

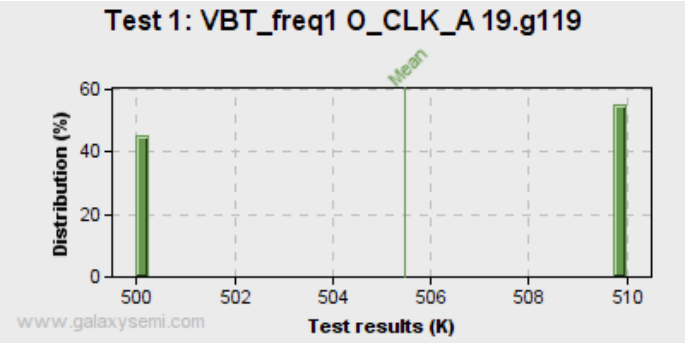
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
0	dssc_pll_freq1 −1	P	450 Khz	550 Khz	Samples	200	3	502.261 Khz	22.9782 Khz	0.7253	0.6925	98.50 %
1	VBT_freq1 O_CLK_A 19.g119	P	450 K	550 K	Samples	197	0	505.482 K	4.98937 K	3.34	2.97	100.00 %
2	VBT_freq1 O_CLK_B 19.e113	P	7.8 M	9.5333 M	Samples	197	0	9.29081 M	0.00273866 M	105.5	29.51	100.00 %
3	VBT_freq1 O_CLK_C 19.g117	P	117 M	143 M	Samples	197	0	130.005 M	0.00499404 M	867.7	867.4	100.00 %
4	VBT_freq1 O_CLK_D 19.g137	P	234 M	371.8 M	Samples	197	0	260.005 M	0.00499403 M	4598.8	1735.7	100.00 %
786000	Soft_Bin parameter	–	n/a .	n/a .	Samples	200	0	984.01	7985.81	n/a .	n/a .	100.00 %
786001	Hard_Bin parameter	–	n/a .	n/a .	Samples	200	0	1.135	1.09672	n/a .	n/a .	100.00 %
786002	Die_X parameter	–	n/a .	n/a .	Samples	200	0	6.4	4.0648	n/a .	n/a .	100.00 %
786003	Die_Y parameter	–	n/a .	n/a .	Samples	200	0	7.35	4.13679	n/a .	n/a .	100.00 %
786004	Test_Time parameter	–	0.0 sec	n/a .	Samples	200	0	0.38732 sec	0.0653873 sec	n/a .	1.97	100.00 %
786006	Testing_Site parameter	–	n/a .	n/a .	Samples	200	0	0	0	n/a .	n/a .	100.00 %
786007	Part_ID parameter	–	n/a .	n/a .	Samples	200	0	100.5	57.8792	n/a .	n/a .	100.00 %

Histogram of Tests

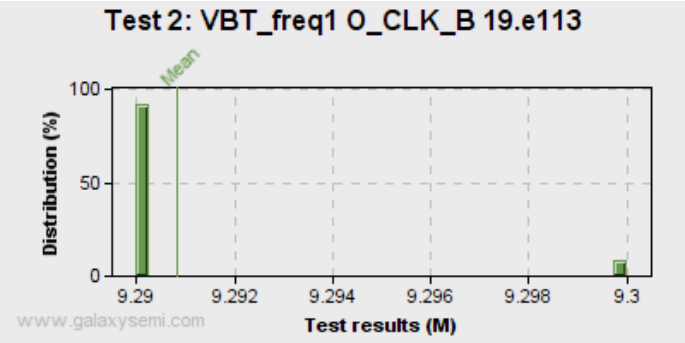
Test	0
Name	dssc_pll_freq1 −1
Test type	Parametric
Low limit	450 Khz
High limit	550 Khz
Exec / Fails	200 / 3 (1.50%)
Mean	502.261 Khz
Sigma	22.9782 Khz
Range	311.402 Khz
Cp / Cpk	0.7253 / 0.6925
Samples	200



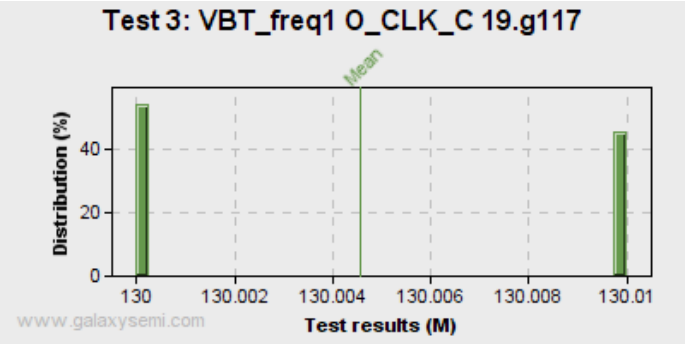
Test	1
Name	VBT_freq1 O_CLK_A 19.g119
Test type	Parametric
Low limit	450 K
High limit	550 K
Exec / Fails	197 / 0 (0.00%)
Mean	505.482 K
Sigma	4.98937 K
Range	10 K
Cp / Cpk	3.34 / 2.97
Samples	200



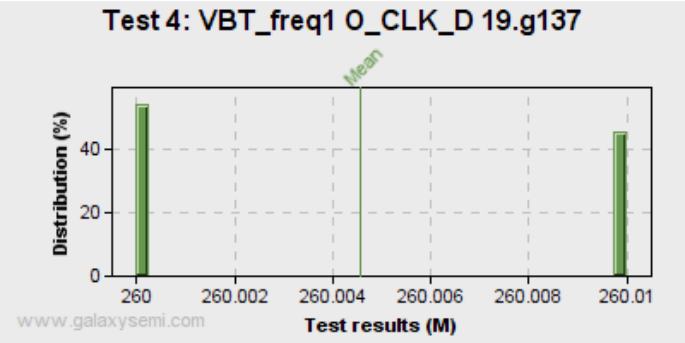
Test	2
Name	VBT_freq1 O_CLK_B 19.e113
Test type	Parametric
Low limit	7.8 M
High limit	9.5333 M
Exec / Fails	197 / 0 (0.00%)
Mean	9.29081 M
Sigma	0.00273866 M
Range	0.01 M
Cp / Cpk	105.5 / 29.51
Samples	200



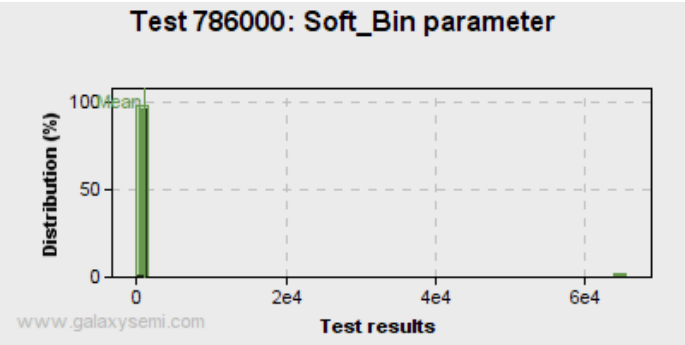
Test	3
Name	VBT_freq1 O_CLK_C 19.g117
Test type	Parametric
Low limit	117 M
High limit	143 M
Exec / Fails	197 / 0 (0.00%)
Mean	130.005 M
Sigma	0.00499404 M
Range	0.01 M
Cp / Cpk	867.7 / 867.4
Samples	200



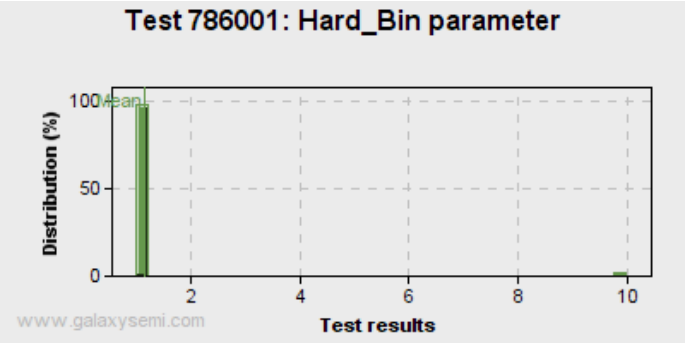
Test	4
Name	VBT_freq1 O_CLK_D 19.g137
Test type	Parametric
Low limit	234 M
High limit	371.8 M
Exec / Fails	197 / 0 (0.00%)
Mean	260.005 M
Sigma	0.00499403 M
Range	0.01 M
Cp / Cpk	4598.8 / 1735.7
Samples	200



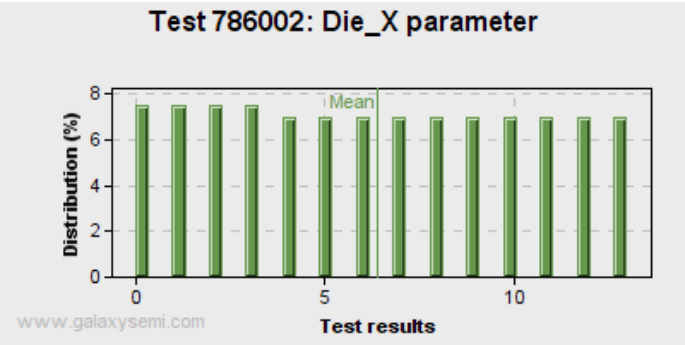
Test	786000
Name	Soft_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	200 / 0 (0.00%)
Mean	984.01
Sigma	7985.81
Range	65534
Cp / Cpk	n/a . / n/a .
Samples	200



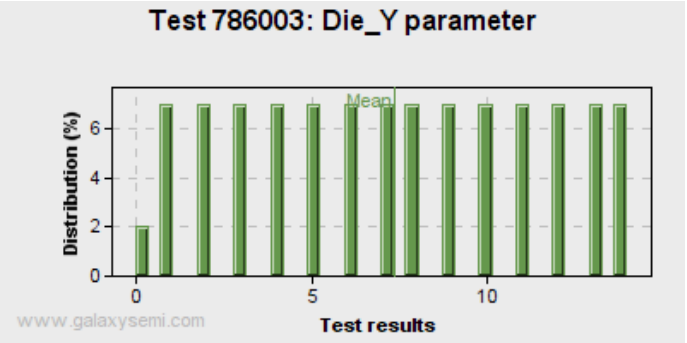
Test	786001
Name	Hard_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	200 / 0 (0.00%)
Mean	1.135
Sigma	1.09672
Range	9
Cp / Cpk	n/a . / n/a .
Samples	200



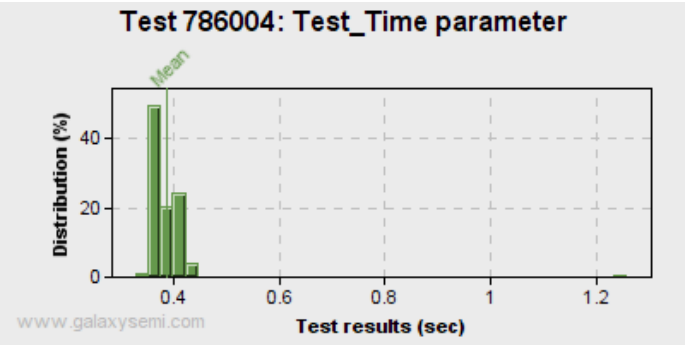
Test	786002
Name	Die_X parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	200 / 0 (0.00%)
Mean	6.4
Sigma	4.0648
Range	13
Cp / Cpk	n/a . / n/a .
Samples	200



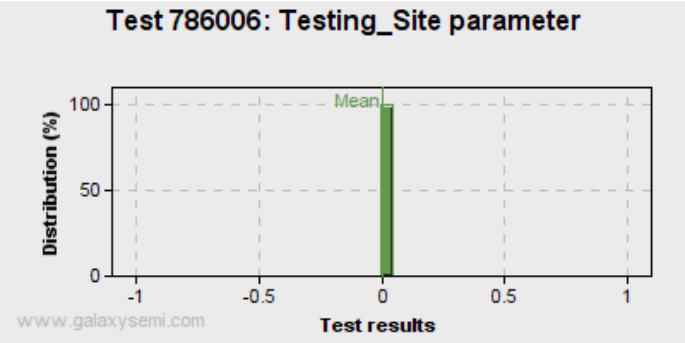
Test	786003
Name	Die_Y parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	200 / 0 (0.00%)
Mean	7.35
Sigma	4.13679
Range	14
Cp / Cpk	n/a . / n/a .
Samples	200



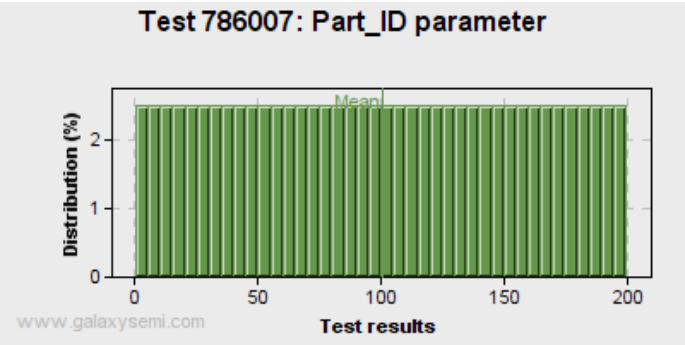
Test	786004
Name	Test_Time parameter
Test type	–
Low limit	0.0 sec
High limit	n/a .
Exec / Fails	200 / 0 (0.00%)
Mean	0.38732 sec
Sigma	0.0653873 sec
Range	0.93 sec
Cp / Cpk	n/a . / 1.97
Samples	200



Test	786006
Name	Testing_Site parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	200 / 0 (0.00%)
Mean	0
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	200



Test	786007
Name	Part_ID parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	200 / 0 (0.00%)
Mean	100.5
Sigma	57.8792
Range	199
Cp / Cpk	n/a . / n/a .
Samples	200



Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart
0	dssc_pll_freq1 −1	0.7253	

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart
0	dssc_pll_freq1 −1	0.6925	

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
0	dssc_pll_freq1 −1	10	3	1.5 %	100.0 %	1.5 %	
–	**Cumul. of failures**	–	**3**	**1.5 %**	**100.0 %**	**1.5 %**	

−− Yield loss: number of failed test executions / number of parts
−− Fail contribution: number of failed test executions / number of parts failed
−− Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **200**
Total patterns detected: **1**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)
3	100.00 %	1.50 %	dssc_pll_freq1 −1 (Test 0)
3	**100 %**	**–**	**Total failures detected**

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')

Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	197	98.5 %	
65535	–	3	1.5 %	
Cumul.	**Cumul.**	**200**	**100.0%**	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	197	98.5 %	
10	–	3	1.5 %	
Cumul.	**Cumul.**	**200**	**100.0%**	

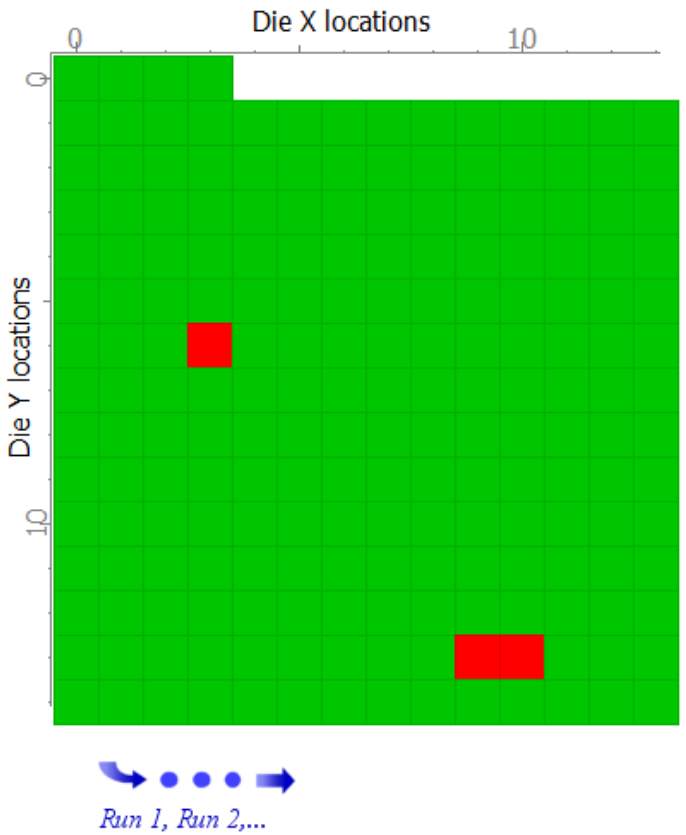
Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	200
Total physical parts tested	200 (only applies to Wafermaps)

List of Individual Maps

Top 10 Software Binning	1	65535
Color		
Pass/Fail	P	F
Percentage	98.5%	1.5%
Total count	197	3

Map style	STRIP map (parts tested are PACKAGED DEVICES!)
Total physical parts tested	200
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Strip started	Thu Oct 17 03:55:42 2024
Strip ended	Thu Oct 17 04:18:25 2024
Wafer tested in	22 minutes 43 seconds
Average device test time	6.815 sec.
Map dimensions	LowX=0, LowY=0, HighX=13, HighY=14



Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	P	197	98.5 %	
65535	–	F	3	1.5 %	
All PASS Bins	**All PASS Bins**	P	**197**	**98.5 %**	
All FAIL Bins	**All FAIL Bins**	F	**3**	**1.5 %**	
ALL Bins	**ALL Bins**	–	**200**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	P	197	98.5 %	
10	–	F	3	1.5 %	
All PASS Bins	**All PASS Bins**	P	**197**	**98.5 %**	
All FAIL Bins	**All FAIL Bins**	F	**3**	**1.5 %**	
ALL Bins	**ALL Bins**	–	**200**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Wed Oct 16 16:40:27 2024
Data processed	85.3 KB (87343 bytes)
Processing time	21.90 seconds
Processing speed	4.0 KB/sec
Examinator expires	Mon Oct 16 2034
(null)	–

File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 2/Project–2/rahmana_i8243_p2.igxl_pll.std
Tests mapping file	n/a
Setup time	Thu Oct 17 03:59:45 2024
Start time	Thu Oct 17 03:55:42 2024
End time	Thu Oct 17 04:18:25 2024
Test duration	22 minutes 43 seconds
Product	n/a
Program	rahmana_i8243_p2.igxl
Revision	n/a
Lot	n/a
Sub–Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	0.388 sec. (excludes tester idle time)
Test time (ALL parts)	0.387 sec. (excludes tester idle time)
Average test time	6.815 sec. / device (includes tester idle time between parts)
Total parts tested	200 – Includes parts retested (if any)
Good parts (Yield)	197 (98.50%) – Includes parts retested (if any)
Bad parts (Yield loss)	3 (1.50%) – Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	–
STDF Version	4.0
Tester name	SNG–UFP–789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG–XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a

Spec_name	n/a
Spec_version	n/a
Family ID	n/a
Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift